


<b>Search Notes</b>  	<b>Application/Control No.</b>  10521846	<b>Applicant(s)/Patent Under Reexamination</b>  YAMAHARA ET AL.
	<b>Examiner</b>  Duc Truong	<b>Art Unit</b>  1796

SEARCHED			
Class	Subclass	Date	Examiner
528	373, 380	12/15/08	DT
428	411.1	12/15/08	DT

SEARCH NOTES		
Search Notes	Date	Examiner
10/521,843 will be reviewed; STN, Invneto name search in 10/521,843	09/23/08	DT

INTERFERENCE SEARCH			
Class	Subclass	Date	Examiner

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